## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



In re application of:

Takenori Hirose, et al.

Application No.:

Filed: Herewith

For: Film Thickness Measuring Method and Apparatus, and Thin Film Device Manufacturing Method and Manufacturing Apparatus Using Same Examiner: U

Unassigned

Art Unit:

Unassigned

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR §1.97 and §1.98

Assistant Commissioner for Patents Washington, D.C. 20231

Sir:

The references cited on attached form PTO/SB/08A are being called to the attention of the Examiner. Copies of the references are enclosed. It is respectfully requested that the cited references be expressly considered during the prosecution of this application, and the references be made of record therein and appear among the "references cited" on any patent to issue therefrom.

As provided for by 37 CFR 1.97(g) and (h), no inference should be made that the information and references cited are prior art merely because they are in this statement and no representation is being made that a search has been conducted or that this statement encompasses all the possible relevant information.

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Respectfully submitted,

Robert C. Colwell Reg. No. 27,431

TOWNSEND and TOWNSEND and CREW LLP Two Embarcadero Center, 8<sup>th</sup> Floor San Francisco, California 94111-3834 Tel: 650-326-2400

Fax: 650-326-2422

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	Substitute for form 1449A/PTO						
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Ĺ,	Hirose, Takenori	First Named Inventor	OIAIEMENT DI ALLEIOANT				
		Group Art Unit					
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	16869P-042900US	Attorney Docket Number	1	of	1	Sheet	

U.S. PATENT DOCUMENTS							
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	FOREIGN PATENT DOCUMENTS							
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	Cite No. <sup>1</sup>	Office <sup>3</sup>		(ind Code <sup>5</sup> ( <i>if known</i> )	or Applicant of Cited Document	Cited Document MM-DD-YYYY	Where Relevant Passages or Relevant Figures Appear	Τ <sup>®</sup>
	AU	JP	2000-241126		Nikon Corp.	09-08-2000		Abstract
	AV	JP	2000-009437		Hitachi, Ltd.	01-14-2000		Abstract
	AW	JP	09-193995		Kanebo, Ltd.	07-29-1997		Abstract
	AX	JP	09-109023		Nova Measuring Instr., Ltd.	04-28-1997		Abstract
	AY	JP	09-007985		Applied Materials	01-10-1997		Abstract
-	AZ	JP	06-252113		Matsushita Electric	09-09-1994		Abstract
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